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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
09/808,750	03/15/2001	Huy Thanh Vo	303.723US1	4340		
21186	7590 06/25/2003					
	SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.			EXAMINER		
P.O. BOX 2938 MINNEAPOLIS, MN 55402			MAI, SON LUU			
			ART UNIT	PAPER NUMBER		
			2818			
			DATE MAILED: 06/25/2003			

Please find below and/or attached an Office communication concerning this application or proceeding.

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· / 		Application No.	Applicant(s)	<u>٠١</u>
	,	09/808,750	VO, HUY THANH	
•	Office Action Summary	Examin r	Art Unit	
•		Son L. Mai	2818	
 Period for	The MAILING DATE of this c mmunical Reply	ation appears on the cover she	et with the correspondence address	
THE M - Extens after S - If the p - If NO p - Failure - Any rep	RTENED STATUTORY PERIOD FOR AILING DATE OF THIS COMMUNICATION of time may be available under the provisions of the may be available under the provisions of the maximum statute. The provision of the maximum statute to reply within the set or extended period for reply will oly received by the Office later than three months after patent term adjustment. See 37 CFR 1.704(b).	ATION. 37 CFR 1.136(a). In no event, however, rication. 19ys, a reply within the statutory minimum tory period will apply and will expire SIX (6). It is not statute, cause the application to become	nay a reply be timely filed of thirty (30) days will be considered timely.) MONTHS from the mailing date of this communication. me ABANDONED (35 U.S.C. § 133)	
1)	Responsive to communication(s) filed	l on		
2a)⊠	This action is FINAL . 2b)☐ This action is non-final.		
	closed in accordance with the practice	or allowance except for forma e under <i>Ex parte Quayle</i> , 193	matters, prosecution as to the merits is 5 C.D. 11, 453 O.G. 213.	;
·	n of Claims	- 11 41 - ···		
	Claim(s) 1-54 is/are pending in the ap	•		
	a) Of the above claim(s) is/are	withdrawn from consideration		
	Claim(s) is/are allowed.			
·	Claim(s) <u>1-54</u> is/are rejected.			
	Claim(s) is/are objected to.			
ا اےارہ Applicatio	Claim(s) are subject to restriction Papers	n and/or election requiremen	i.	
·	ne specification is objected to by the E			
10)∐ Ti	ne drawing(s) filed on is/are: a)	☐ accepted or b)☐ objected to	by the Examiner.	
	Applicant may not request that any object			
	ne proposed drawing correction filed o		disapproved by the Examiner.	
	If approved, corrected drawings are required.	, ,		
	ne oath or declaration is objected to by	the Examiner.		
	der 35 U.S.C. §§ 119 and 120			
	cknowledgment is made of a claim for	r foreign priority under 35 U.S	.C. § 119(a)-(d) or (f).	
a) <u></u>	All b) Some * c) None of:			
1	. Certified copies of the priority do			
2	. Certified copies of the priority do	cuments have been received	in Application No	
	Copies of the certified copies of t application from the Internati e the attached detailed Office action for	onal Bureau (PCT Rule 17.2(a)).	
		•	S.C. § 119(e) (to a provisional application	n).
a) [The translation of the foreign langu	age provisional application ha	as been received.	,
Attachment(s		• • • • • • • • • • • • • • • • • • • •	30	
2) 🔲 Notice o	of References Cited (PTO-892) of Draftsperson's Patent Drawing Review (PTO- tion Disclosure Statement(s) (PTO-1449) Pape	-948) 5) 🗌 Notic	riew Summary (PTO-413) Paper No(s) e of Informal Patent Application (PTO-152)	
6. Patent and Trade TO-326 (Rev.		Office Action Summary	Part of Paper No. 16	

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DETAILED ACTION

The Response under 37 CFR § 1.111 filed 06-11-03 has been entered. Claims
 1-54 are pending in the application.

Claim Rejections - 35 USC § 103

- 2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 3. Claims 1-54 are rejected under 35 U.S.C. 103(a) as being unpatentable over Tanoi (U.S. Patent 5,708,621).

Regarding claims 1, 8, 15, 26, 30, 42 and 45, Tanoi discloses a memory array (1 in fig. 1) comprising: a number of memory cells (6) having a first source/drain region and a second source/drain region and a gate region (parts of an access transistor in a dynamic random access memory); a number of source lines (not shown) coupled to the first source/drain region of at least one memory cell; a number of bit lines (4) coupled to the second source/drain region of at least one memory cell; a number of wordlines (2) coupled to the gate region of at least one memory cell; a strapping line (118 in fig. 16) of lower resistance than the wordlines coupled to a single wordline wherein the strapping line bypasses a portion of the single wordline, and wherein the strapping line is spaced apart from adjacent conductive structures by a distance greater than a wordline pitch (fig. 18); and at least two channels (122, 126 in fig. 18) connecting the strapping line to a first and second end of the portion of the single wordline.

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Regarding claims 2, 3, 6, 7, 9, 10, 16, 17, 20, 21, 27, 28, 31, 32, 39, 44, 46, 47, 50, 51, Tanoi teaches at column 7, lines 54-57, the strapping lines comprise metal.

Regarding claims 4, 29, Tanoi shows in figure 16, the portion of the wordline bypassed by the strapping line comprises a first half of the memory cells coupled to the wordline.

Regarding claims 5, 19, 37 and 49, Tanoi teaches a memory array, comprising: a number of memory cells having a first source/drain region and a second source/drain region and a gate region (parts of an access transistor in a dynamic random access memory); a number of source lines (not shown) coupled to the first source/drain region of at least one memory cell; a number of bit lines (4 in fig. 1) coupled to the second source/drain region of at least one memory cell; a number of wordlines (2 in fig. 1) coupled to the gate region of at least one memory cell; a plurality of strapping lines (50 in fig. 4) of lower resistance than the wordlines coupled to at least one of the number of wordlines wherein the strapping lines (lines 50 consisting of two strapping lines joining at interconnecting plug 60) bypass a plurality of portions (54, 56) of a single wordline; and a plurality of channels (60 in fig. 6) connecting the plurality of strapping layers to the wordline.

Regarding claims 11, 22, 33, Tanoi shows in figure 4, the portions (38, 40, 42) of the wordlines (37) in the array bypassed by the number of strapping devices (line 36 has 2 portions) comprises a plurality of end portions (44, 46,48) of the wordlines.

Regarding claims 12, 23, 34, 52, Tanoi shows in figure 4, the strapping devices are located on alternating wordlines in the array.

Regarding claims 13, 24, 35, 53, Tanoi shows in figure 16, the strapping devices (108, 118) are located on adjacent wordlines and staggered along the wordlines such that the portions of the adjacent wordlines that are bypassed are not adjacent to each other.

Regarding claims 14, 18, 25, 36, 54, Tanoi shows in figure 16, the strapping devices (108, 118) strap a first half portion of a number of even wordlines in the array and a second half portion of a number of odd wordlines.

Regarding claims 38, 43, the method of reducing a wordline RC time constant reads on figure 16 of Tanoi, wherein activating a second number of transistors coupled to a second portion (114) of a wordline comprises: sending a signal through a first channel (112) to a metal strapping line (108); sending the signal through the metal strapping line; and sending the signal through a second channel (116) to the second portion (114) of the wordline.

Regarding claim 40, the method of reducing a wordline RC time constant as claimed reads on figure 16 wherein activating a first number of transistors coupled to a first portion (110) of a wordline comprising activating a first number of transistors coupled to a first half of the wordline.

Regarding claims 41, 48, the method of reducing a wordline RC time constant reads on figure 4, wherein activating a selected row in a memory array comprises bypassing multiple portions (38, 40) of the wordline (37) using multiple strapping devices (strapping line 36 has 2 portions connecting at interconnecting plug 46) of lower resistance than the wordline.

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Tanoi does not explicitly depict a width of the strapping line being greater than a width of the wordlines as now included in the independent claims 1, 5, 8, 15, 19, 26, 30, 37, 42, 45 and 49. As is well known in the art, a wider conductor has lower resistance. Tanoi shows in one embodiment in figures 16-18, a strapping line 118 having low resistance (column 9, lines 33-41) and gaps between the strapping lines are large to accommodate wider strapping lines. Thus, it would have been obvious to one of ordinary skill in the art at the time of the invention to make the strapping lines wider to lower resistance of the strapping lines and to reduce propagation delay of the strapping lines.

Response to Arguments

4. Applicant's arguments filed 06-11-03 have been fully considered but they are not persuasive. In response to applicant's argument that the examiner's conclusion of obviousness is based upon improper hindsight reasoning, it must be recognized that any judgment on obviousness is in a sense necessarily a reconstruction based upon hindsight reasoning. But so long as it takes into account only knowledge which was within the level of ordinary skill at the time the claimed invention was made, and does not include knowledge gleaned only from the applicant's disclosure, such a reconstruction is proper. See *In re McLaughlin*, 443 F.2d 1392, 170 USPQ 209 (CCPA 1971). Consider the description at column 9, lines 56-67 of Tanoi (U.S. Patent 5,708,621) which has a desire for low resistance strapping lines. One would strive to make wide strapping lines to reduce propagation delay due to the resistance of the strapping lines.

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Conclusion

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5. THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time

policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE

MONTHS from the mailing date of this action. In the event a first reply is filed within

TWO MONTHS of the mailing date of this final action and the advisory action is not

mailed until after the end of the THREE-MONTH shortened statutory period, then the

shortened statutory period will expire on the date the advisory action is mailed, and any

extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of

the advisory action. In no event, however, will the statutory period for reply expire later

than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Son L. Mai whose telephone number is 305-3497. The

examiner can normally be reached on 8am to 6pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, David Nelms can be reached on 308-4910. The fax phone numbers for the

organization where this application or proceeding is assigned are 308-7724 for regular

communications and 308-7724 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or

proceeding should be directed to the receptionist whose telephone number is 308-0956.

06-19-2003

Son L. Mai

Primary Examiner

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